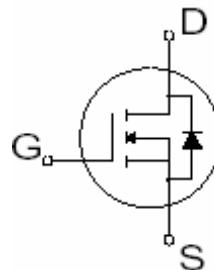


- Extremely high dv/dt capability
- Low Gate Charge Qg results in Simple Drive Requirement
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability



V_{DSS} = 900V

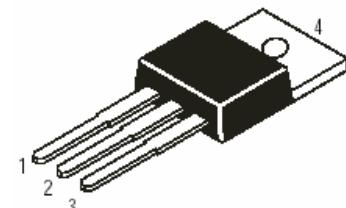
I_{D25} = 4A

R_{DSON} = 4.2 Ω

Description

StarMOS is a new generation of high voltage N-Channel enhancement mode power MOSFETs.

This new technology minimises the JFET effect, increases packing density and reduces the on-resistance. StarMOS also achieves faster switching speeds through optimised gate layout with planar stripe DMOS technology.



Pin1-Gate
Pin2-Drain
Pin3-Source

Application

- Switching application

Absolute Maximum Ratings

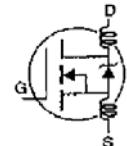
| | Parameter | Max. | Units |
|---------------------------------------|--|----------------------|-------|
| I _D @T _c =25°C | Continuous Drain Current,V _{GS} @10V | 4 | A |
| I _D @T _c =100°C | Continuous Drain Current,V _{GS} @10V | 2.3 | |
| I _{DM} | Pulsed Drain Current ① | 16 | |
| P _D @T _c =25°C | Power Dissipation | 140 | W |
| | Linear Derating Factor | 1.12 | W/°C |
| V _{GS} | Gate-to-Source Voltage | ±30 | V |
| E _{AS} | Single Pulse Avalanche Energy ② | 170 | mJ |
| I _{AR} | Avalanche Current ① | 2.2 | A |
| E _{AR} | Repetitive Avalanche Energy ① | 8.5 | mJ |
| dv/dt | Peak Diode Recovery dv/dt ③ | 4.0 | V/ns |
| T _J | Operating Junction and Storage Temperature Range | - 55 to +150 | C |
| T _{STG} | Soldering Temperature, for 10 seconds | 300(1.6mm from case) | |
| | Mounting Torque,6-32 or M3 screw | 10 lbf.in(1.1N.m) | |

Thermal Resistance

| | Parameter | Min. | Typ. | Max. | Units |
|------------------|-----------------------------------|------|------|------|-------|
| R _{θJC} | Junction-to-case | — | — | 0.89 | C/W |
| R _{θCS} | Case-to-Sink,Flat,Greased Surface | — | 0.5 | — | |
| R _{θJA} | Junction-to-Ambient | — | — | 62.5 | |

Electrical Characteristics @TJ=25°C(unless otherwise specified)

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--|--------------------------------------|------|------|------|-------|---|
| V _{(BR)DSS} | Drain-to-Source Breakdown Voltage | 900 | — | — | V | V _{GS} =0V, I _D =250μA |
| △V _{(BR)DSS} /△T _J | Breakdown Voltage Temp.Coefficient | — | 1.05 | — | V/C | Reference to 25°C, I _D =250μA |
| R _{D(on)} | Static Drain-to-Source On-resistance | — | 3.5 | 4.2 | Ω | V _{GS} =10V, I _D =2A ④ |
| V _{GS(th)} | Gate Threshold Voltage | 3.0 | — | 5.0 | V | V _{DS} =V _{GS} , I _D =250μA |
| g _{fs} | Forward Transconductance | — | 2.0 | — | S | V _{DS} =50V, I _D =2A |
| I _{DSS} | Drain-to-Source Leakage current | — | — | 10 | μ A | V _{DS} =900V, V _{GS} =0V |
| | | — | — | 100 | μ A | V _{DS} =720V, V _{GS} =0V, T _J =125°C |
| I _{GSS} | Gate-to-Source Forward leakage | — | — | 100 | nA | V _{GS} =30V |
| | Gate-to-Source Reverse leakage | — | — | -100 | nA | V _{GS} =-30V |
| Q _g | Total Gate Charge | — | 17 | 22 | | I _D =4A |
| Q _{gs} | Gate-to-Source charge | — | 4.5 | — | | V _{DS} =720V |
| Q _{gd} | Gate-to-Drain("Miller") charge | — | 7.5 | — | | V _{GS} =10V See Fig.6 and 13④ |
| t _{d(on)} | Turn-on Delay Time | — | 25 | 60 | | V _{DD} =450V |
| t _r | Rise Time | — | 50 | 110 | | I _D =4A |
| t _{d(off)} | Turn-Off Delay Time | — | 40 | 90 | | R _G =25Ω |
| t _f | Fall Time | — | 35 | 80 | | |
| L _D | Internal Drain Inductance | — | 4.5 | — | nH | Between lead, 6mm(0.25in.) from package and center of die contact |
| L _S | Internal Source Inductance | — | 7.5 | — | | |
| C _{iss} | Input Capacitance | — | 740 | 960 | | V _{GS} =0V |
| C _{oss} | Output Capacitance | — | 65 | 85 | pF | V _{DS} =25V |
| C _{rss} | Reverse Transfer Capacitance | — | 5.6 | 7.3 | | t=1.0MHz See Figure 5 |



Source-Drain Ratings and Characteristics

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|-----------------|---|---|------|------|-------|---|
| I _s | Continuous Source Current (Body Diode) | — | — | 4 | A | MOSFET symbol showing the integral reverse p-n junction diode. |
| I _{SM} | Pulsed Source Current (Body Diode) ① | — | — | 16 | | |
| V _{SD} | Diode Forward Voltage | — | — | 1.4 | V | T _J =25°C, I _s =4A, V _{GS} =0V ④ |
| t _{rr} | Reverse Recovery Time | — | 450 | — | nS | T _J =25°C, I _s =4A |
| Q _{rr} | Reverse Recovery Charge | — | 3.5 | — | nC | di/dt=100A/μs ④ |
| t _{on} | Forward Turn-on Time | Intrinsic turn-on time is negligible (turn-on is dominated by L _s + L _d) | | | | |

Notes:

- ① Repetitive rating;pulse width limited by max.junction temperature(see figure 11)
- ② L = 67mH, I_{AS} = 4A, V_{DD} = 50V, R_G = 25Ω, Starting T_J = 25°C

③ I_{SD}≤4A,di/dt≤200A/μs,V_{DD}≤V_{(BR)DSS}, T_J≤25°C

④ Pulse width≤300 μs; duty cycle≤2%